

General Description

The MY30N50TP is silicon N-channel Enhanced VDMOSFETS, obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy.

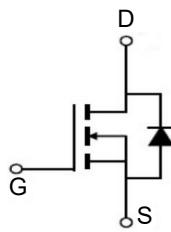
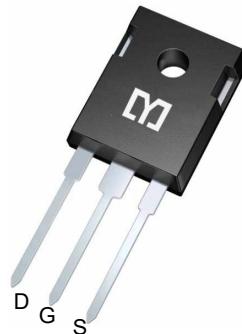


Features

V _{DSS}	500	V
I _D	30	A
P _D (T _C = 25 °C)	250	W
R _{DS(ON)} (at V _{GS} = 10V)	< 0.12	Ω

Application

- High efficiency switch mode power supplies
- Power factor correction
- Electronic lamp ballast



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
MY30N50TP	TO-247	MY30N50TP	600

Absolute Maximum Ratings (T_c=25 °C unless otherwise noted)

Symbol	Parameter	Rating	Units
V _{DSS}	Drain-to-Source Voltage	500	V
I _D	Continuous Drain Current	30	A
	Continuous Drain Current T _c = 100 °C	18.6	A
I _{DM} ^{a1}	Pulsed Drain Current	120	A
V _{GS}	Gate-to-Source Voltage	±30	V
E _{AS} ^{a2}	Single Pulse Avalanche Energy	3200	mJ
dv/dt ^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P _D	Power Dissipation	250	W
	Derating Factor above 25°C	2	W/°C
T _J , T _{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	°C
T _L	Maximum Temperature for Soldering	300	°C

Electrical Characteristics ($T_c=25^\circ\text{C}$, unless otherwise noted)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	500	--	--	V
$\Delta BV_{DSS}/ \Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu\text{A}, \text{Reference } 25^\circ\text{C}$	--	0.60	--	$^\circ\text{C}$
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=500\text{V}, V_{GS}=0\text{V}, T_a = 25^\circ\text{C}$	--	--	1	μA
		$V_{DS}=400\text{V}, V_{GS}=0\text{V}, T_a = 125^\circ\text{C}$	--	--	100	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{DS}=0\text{V}, V_{GS}=30\text{V}$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{DS}=0\text{V}, V_{GS}=-30\text{V}$	--	--	-100	nA
ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10\text{V}, I_D=15\text{A}$	--	0.09	0.12	Ω
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	--	4.0	V
Pulse width $tp \leqslant 300\mu\text{s}, \delta \leqslant 2\%$						
Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Trans conductance	$V_{DS}=15\text{V}, I_D = 15\text{A}$	--	33	--	S
R_g	Gate resistance	$f = 1.0\text{MHz}$	--	3.5	--	Ω
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V} V_{DS} = 25\text{V} f = 1.0\text{MHz}$	--	7857.9	--	pF
C_{oss}	Output Capacitance		--	751.2	--	
C_{rss}	Reverse Transfer Capacitance		--	29.7	--	
Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 30\text{A} V_{DD} = 250\text{V} R_G = 25\Omega$	--	68	--	ns
tr	Rise Time		--	141	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	213	--	
tf	Fall Time		--	97.3	--	
Q_g	Total Gate Charge	$I_D = 30\text{A} V_{DD} = 400\text{V} V_{GS} = 10\text{V}$	--	153	--	nC
Q_{gs}	Gate to Source Charge		--	36.3	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	57.9	--	

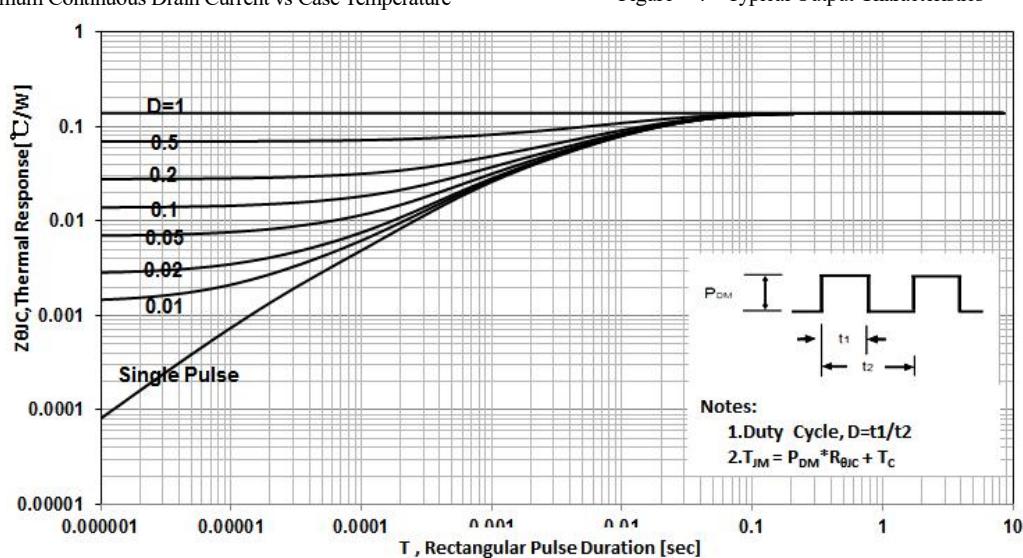
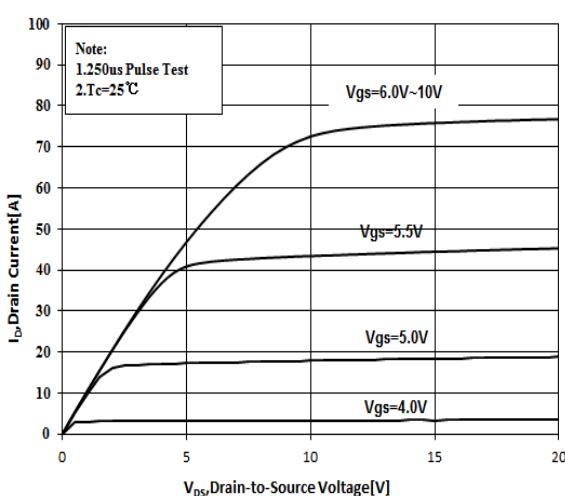
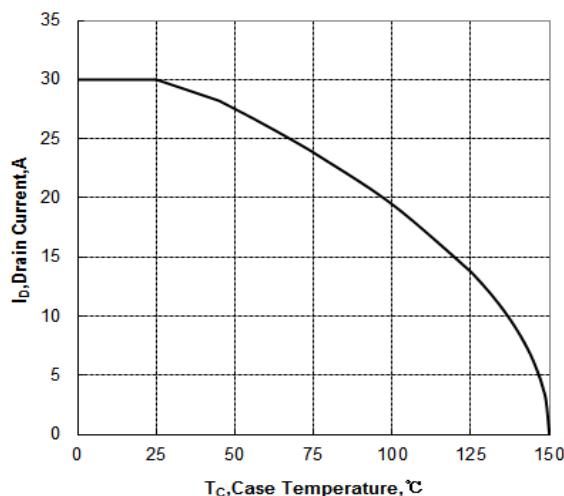
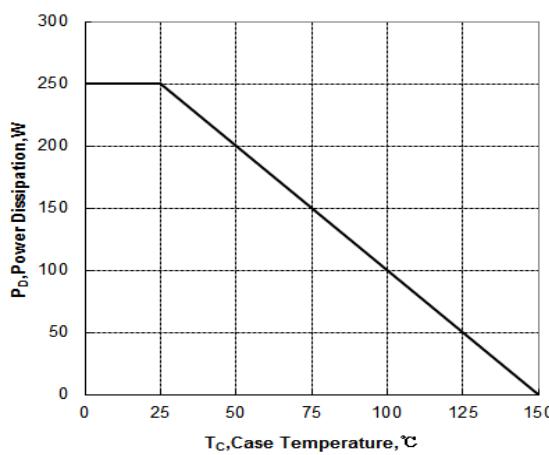
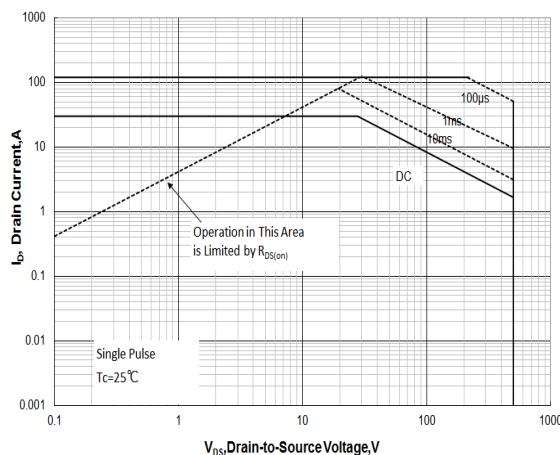
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current (Body Diode)		--	--	30	A
I _{SM}	Maximum Pulsed Current (Body Diode)		--	--	120	A
V _{SD}	Diode Forward Voltage	I _S =30A, V _{GS} =0V	--	--	1.5	V
t _{rr}	Reverse Recovery Time	I _S =30A, T _j = 25° C dI _F /dt=100A/us, V _{GS} =0V	--	482	--	ns
Q _{rr}	Reverse Recovery Charge		--	8.5	--	μC
I _{RRM}	Reverse Recovery Current		--	33.2	--	A

Pulse width t_p≤300μs, δ ≤2%

Symbol	Parameter	Max.	Units
R _{θ JC}	Junction-to-Case	0.5	°C/W
R _{θ JA}	Junction-to-Ambient	40	°C/W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature^{a2}: L=10.0mH, I_D=25.3A, Start T_j=25°C^{a3}: I_{SD} =30A,di/dt ≤300A/us,V_{DD}≤BV_{DS}, Start T_j=25°C

Ratings and Characteristic curves



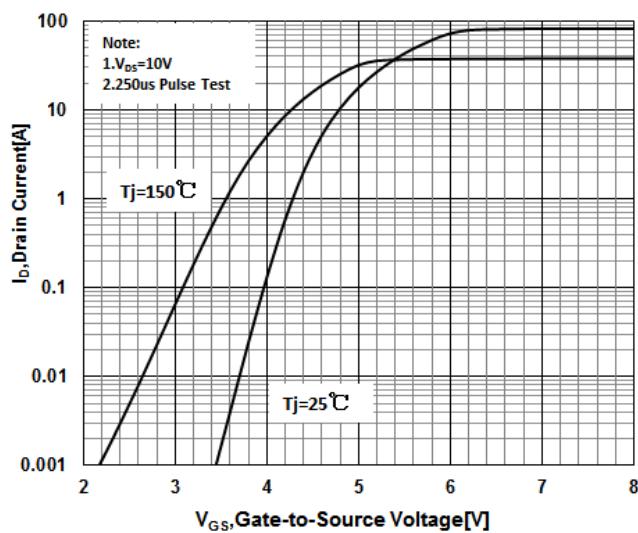


Figure 6 Typical Transfer Characteristics

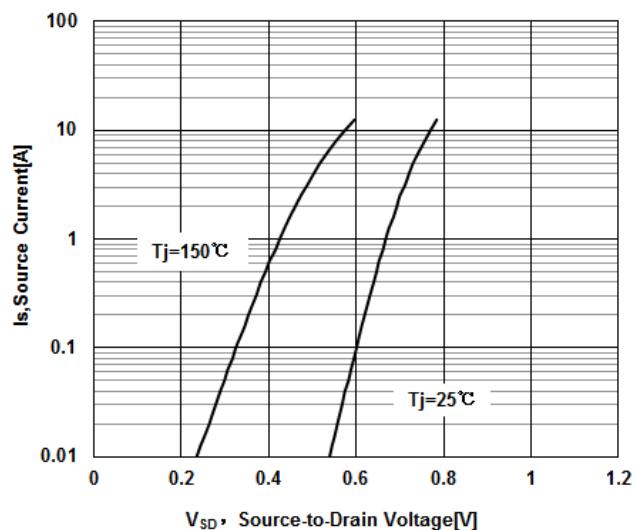


Figure 7 Typical Body Diode Transfer Characteristics

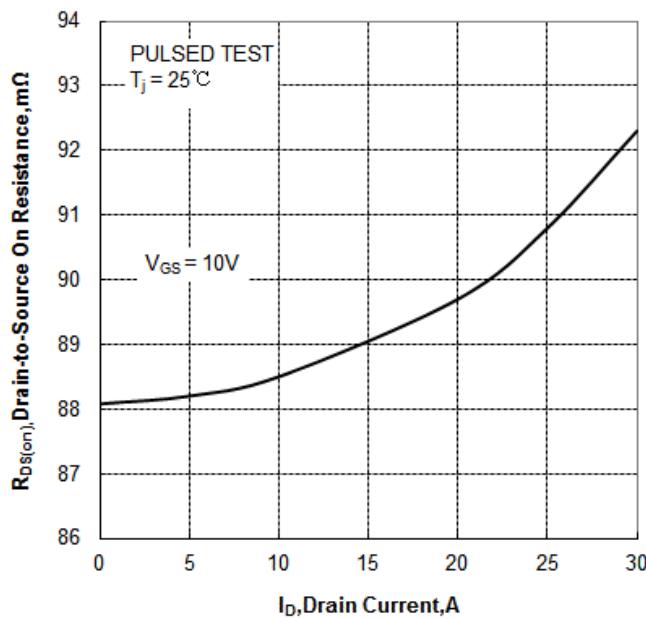


Figure 8 Typical Drain to Source ON Resistance vs Drain Current

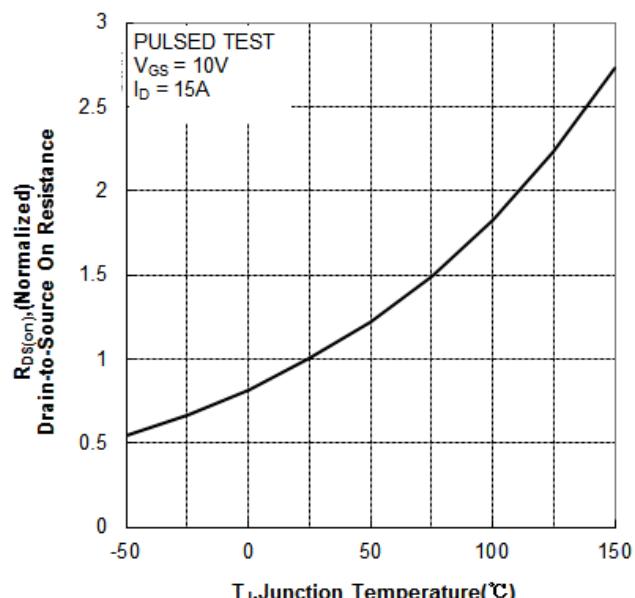


Figure 9 Typical Drian to Source on Resistance vs Junction Temperature

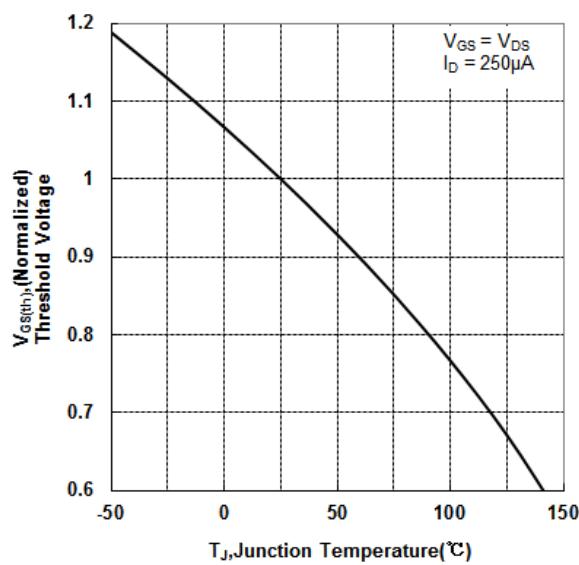


Figure 10 Typical Threshold Voltage vs Junction Temperature

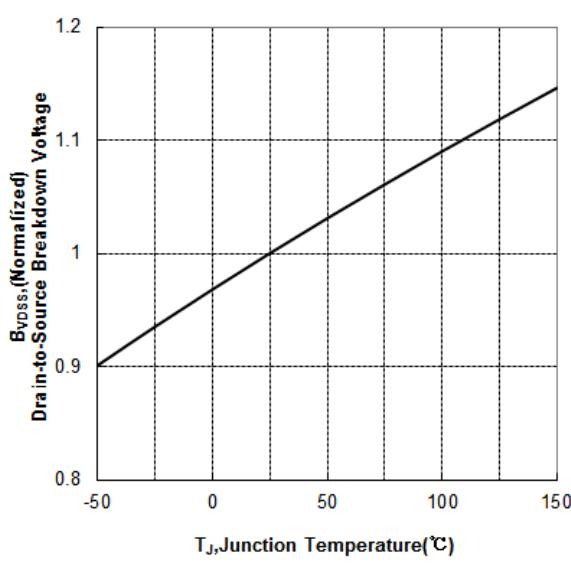


Figure 11 Typical Breakdown Voltage vs Junction Temperature

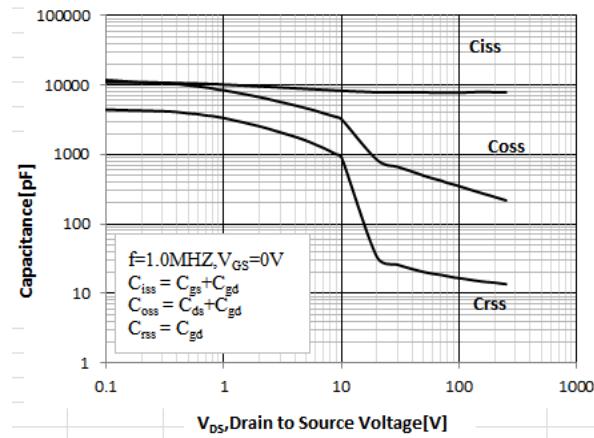


Figure 12 Typical Capacitance vs Drain to Source Voltage

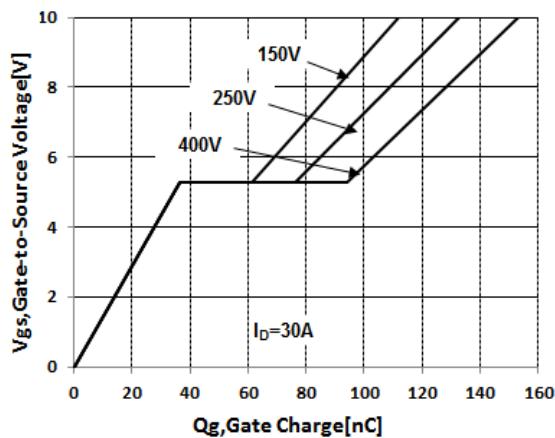


Figure 13 Typical Gate Charge vs Gate to Source Voltage

Test Circuit and Waveform

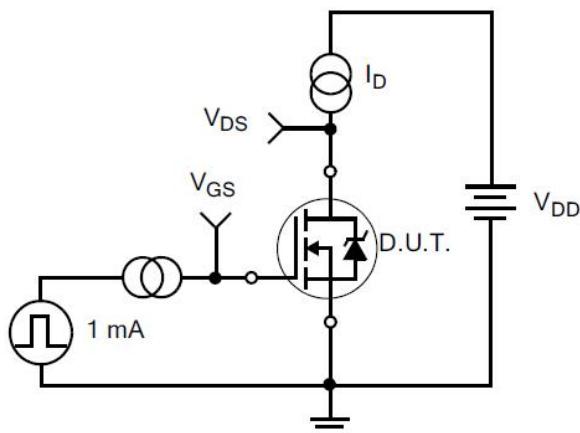


Figure 14. Gate Charge Test Circuit

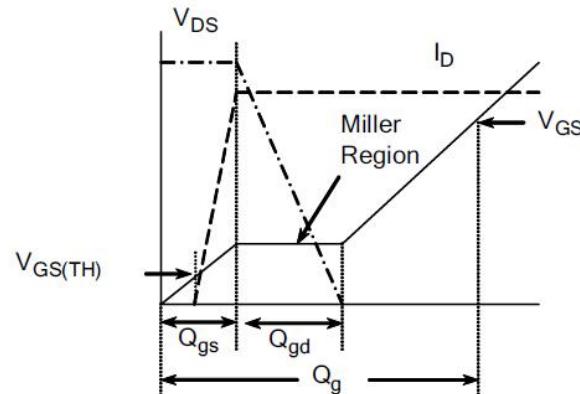


Figure 15. Gate Charge Waveforms

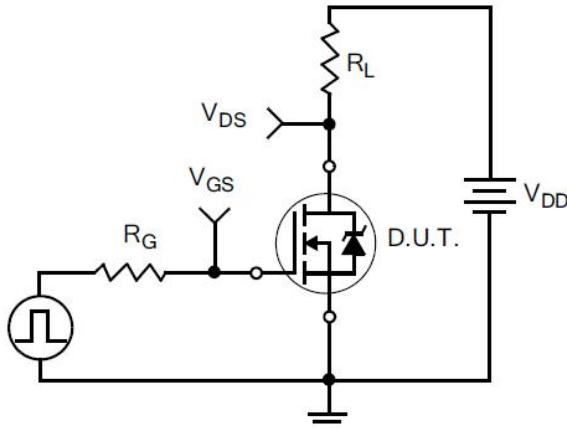


Figure 16. Resistive Switching Test Circuit

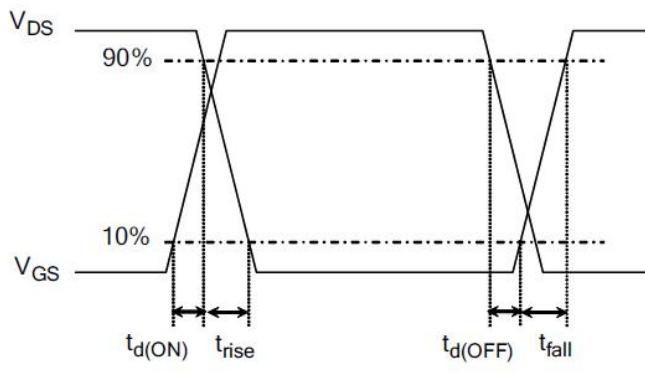


Figure 17. Resistive Switching Waveforms

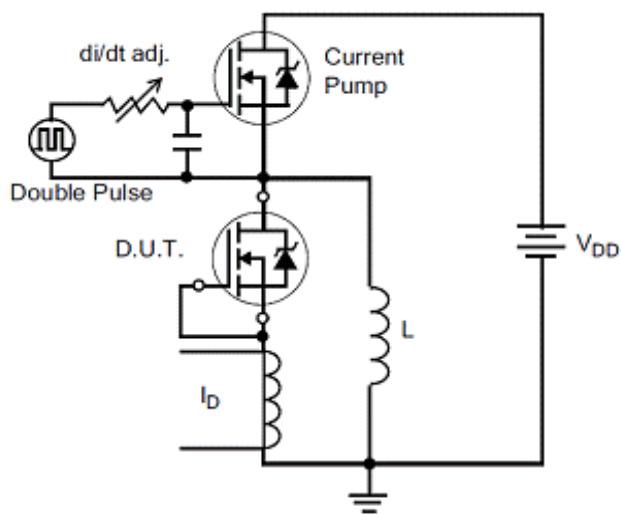


Figure 18. Diode Reverse Recovery Test Circuit

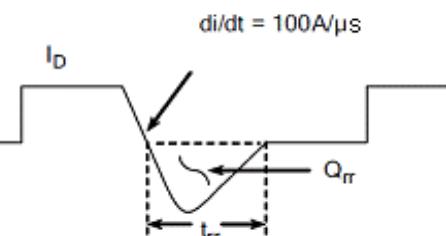


Figure 19. Diode Reverse Recovery Waveform

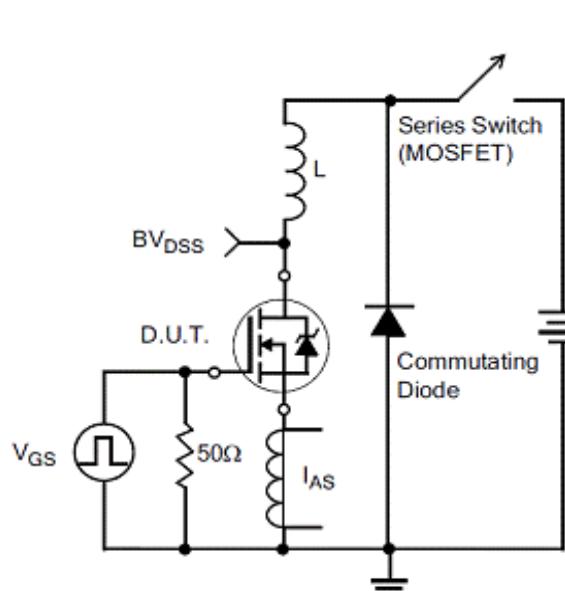


Figure 20. Unclamped Inductive Switching Test Circuit

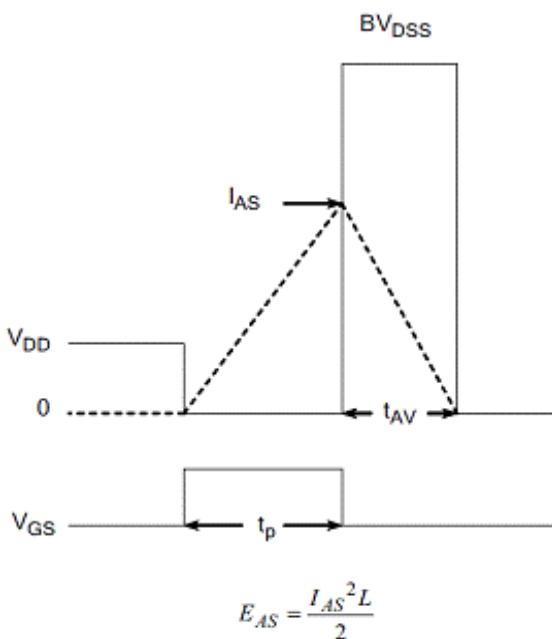
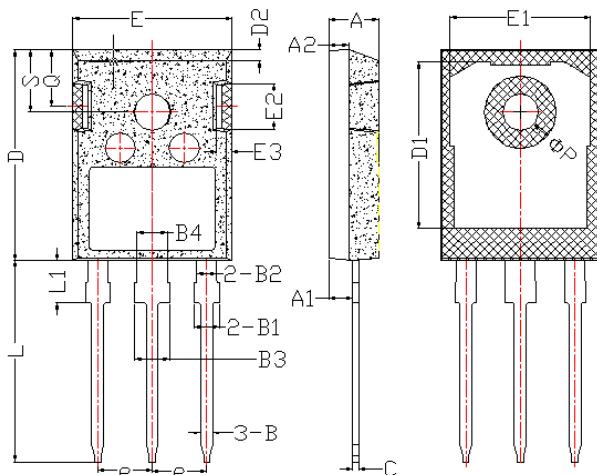


Figure 21. Unclamped Inductive Switching Waveform

Package Mechanical Data-TO-247 Single



Items	Values(mm)	
	MIN	MAX
A	4.6	5.2
A1	2.2	2.6
B	0.9	1.4
B1	1.75	2.35
B2	1.75	2.15
B3	2.8	3.35
B4	2.8	3.15
C	0.5	0.7
D	20.60	21.30
D1	16	18
E	15.5	16.10
E1	13	14.7
E2	3.80	5.3
E3	0.8	2.60
e	5.2	5.7
L	19	20.5
L1	3.9	4.6
ΦP	3.3	3.70
Q	5.2	6.00
S	5.8	6.6